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UNITED STATES PATENT AND TRADEMARK OFFICE

Patent No.: US 6,947,871 B2 Atty. Docket No.: HSJ920030179US1

Issued: September 20, 2005

Inventor(s): Youping Deng, Christopher D. Keener and Jinsong Wang

Entitled: **YIELD/QUALITY IMPROVEMENT USING CALCULATED FAILURE RATE DERIVED FROM MULTIPLY COMPONENT LEVEL PARAMETERS**

Certificate of Corrections Branch
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

LETTER CALLING ATTENTION TO ERRORS IN PATENT

It is noted that a typographical printing error appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

Column 4, line 52: replace "projFRate = 1 – { [1-f(x1)] * [1-f(x2)] * … * [1-f(xNp)]} /Np)" with -- projFRate = 1 – { [1-f(x1)] * [1-f(x2)] * … * [1-f(xNp)] }**(1/Np)--.

Column 6, line 46: replace "projFRate = 1 – { [1-f(x1)] * [1-f(x2)] * … * [1-f(xNp)]} /Np)" with -- projFRate = 1 – { [1-f(x1)] * [1-f(x2)] * … * [1-f(xNp)] }**(1/Np)--.

Column 8, line 12: insert --return--after "field" and before "rate"

Dated: November 8, 2005

Respectfully submitted:

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